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Tutorial Title:	A Tutorial Introduction to TTCN-3 Language
Intended Audience:	Testing Community

Tutorial Overview

The Testing and Test Control Notation Version 3 (TTCN-3) is an internationally standardized language for defining test specifications for a wide range of systems. It allows the concise description of test behavior by unambiguously defining the meaning of a test case pass or fail.

This tutorial provides a solid introduction to the TTCN-3 language and its use. All the important concepts and constructs of the language are explained in this tutorial, with emphasis on practical examples.

Tutorial Structure and Timing

The tutorial introduction to TTCN-3 Language will cover the following topics.

1. Motivation
2. History
3. Differences between TTCN-2 and TTCN-3
4. Application Areas
5. Principles of TTCN-3
6. TTCN 3 Architecture - The Building Blocks
7. Language Toolkit
8. Examples
9. Q & A

The tutorial will last for 4 hours.

Tutorial Materials

1. ETSI ES 201 873-2: "Methods for Testing and Specification (MTS); The Testing and Test Control Notation version 3; Part 2: TTCN-3 Tabular presentation Format (TFT)"
2. ETSI ES 201 873-3: "Methods for Testing and Specification (MTS); The Testing and Test Control Notation version 3; Part 3: TTCN-3 Graphical presentation Format (GFT)"
3. ETSI ES 201 873-5: "Methods for Testing and Specification (MTS); The Testing and Test Control Notation version 3; Part 5: TTCN-3 Runtime Interface (TRI)"
4. ETSI ES 201 873-6: "Methods for Testing and Specification (MTS); The Testing and Test Control Notation version 3; Part 6: TTCN-3 Control Interface (TCI)"
5. ETSI ES 201 873-7: "Methods for Testing and Specification (MTS); The Testing and Test Control Notation version 3; Part 7: Using ASN.1 with TTCN-3"
6. ETSI ES 201 873-8: "Methods for Testing and Specification (MTS); The Testing and Test Control Notation version 3; Part 8: The IDL to TTCN-3 Mapping"

7. ETSI ES 201 873-9: "Methods for Testing and Specification (MTS); The Testing and Test Control
8. Notation version 3; Part 9: Using XML schema with TTCN-3"